



Title of Change:	Adding Nitride Passivation layer on P-Zener devices
Proposed first ship date:	30 September 2016 or earlier upon customer approval
Contact information:	Contact your local ON Semiconductor Sales Office or <Syahrul.SamsuddinA.Rahim@onsemi.com>
Samples:	Contact your local ON Semiconductor Sales Office
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Nicky.Siu@onsemi.com >
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change. ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <PCN.Support@onsemi.com>.
Change Part Identification:	Affected products will be identified with date code
Change category:	<input checked="" type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____

Change Sub-Category(s):

<input type="checkbox"/> Manufacturing Site Change/Addition	<input type="checkbox"/> Material Change	<input type="checkbox"/> Datasheet/Product Doc change
<input checked="" type="checkbox"/> Manufacturing Process Change	<input type="checkbox"/> Product specific change	<input type="checkbox"/> Shipping/Packaging/Marking
		<input type="checkbox"/> Other: _____

Sites Affected:

<input type="checkbox"/> All site(s)	<input type="checkbox"/> not applicable	<input checked="" type="checkbox"/> ON Semiconductor site(s) : ON ISMF, Malaysia	<input type="checkbox"/> External Foundry/Subcon site(s)
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Description and Purpose:

As a part of ON Semiconductor’s continuous improvement, this FPCN is issued to announce that Passivation change will occur with adding a Nitride Passivation Layer on P-Zener devices

Reliability Data Summary:

QV DEVICE NAME : SZMMBZ33VALT1G
PACKAGE: SOT-23

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0/231
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C. Performed prior to TC and HAST test.	Post PC	0/462
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/231
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/231



AEC 1 pager
SZMMBZ33VALT1G

To access file attachments on pdf copy of PCN, please be guided by the steps below:

1. Download pdf copy of the PCN to your computer
2. Open the downloaded pdf copy of the PCN
3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field
4. Then click on the attached file/s

Electrical Characteristic Summary:
Electrical characteristics are not impacted



List of affected Standard Parts:	
Part Number	Qualification Vehicle
S1ZMMBZ27VALT3G	
S2ZMMBZ18VALT1G	
SMMBZ33VALT1G	
SMMBZ33VALT3G	
SMQA1000T1G	
SMQA2000T1G	
SZMMBZ15VALT1G	
SZMMBZ15VALT3G	
SZMMBZ15VAWT1G	
SZMMBZ16VALT1G	
SZMMBZ16VTALT1G	
SZMMBZ18VALT1G	
SZMMBZ18VALT3G	
SZMMBZ20VALT1G	
SZMMBZ20VALT3G	
SZMMBZ20VAWT1G	
SZMMBZ27VALT1G	
SZMMBZ27VALT3G	
SZMMBZ27VAWT1G	
SZMMBZ33VALT1G	
SZMMBZ33VALT3G	
SZMMBZ33VAWT1G	
SZMMBZ4252T1G	
SZMMBZ4252T3G	
SZMMQA15VT1G	
SZMMQA27VT1G	
SZMMQA33VT1G	
SZSM12T1G	
SZSMS15T1G	
SZSMS24CT1G	
SZSMS24T1G	
SZMMQA18VT1G	
	SZMMBZ33VALT1G